SN74LVCH16374A 16-BIT EDGE-TRIGGERED D-TYPE FLIP-FLOP WITH 3-STATE OUTPUTS

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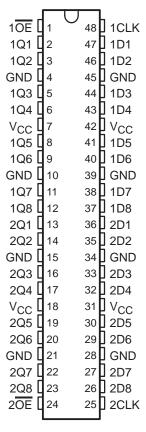
- Member of the Texas Instruments
 Widebus™ Family
- EPIC[™] (Enhanced-Performance Implanted CMOS) Submicron Process
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 2 V at V_{CC} = 3.3 V, T_A = 25°C
- Power Off Disables Outputs, Permitting Live Insertion
- Supports Mixed-Mode Signal Operation on All Ports (5-V Input and Output Voltages With 3.3-V V_{CC})
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Bus Hold on Data Inputs Eliminates the Need for External Pullup/Pulldown Resistors
- Package Options Include Plastic 300-mil Shrink Small-Outline (DL) and Thin Shrink Small-Outline (DGG) Packages

description

This 16-bit edge-triggered D-type flip-flop is designed for 1.65-V to 3.6-V V_{CC} operation.

The SN74LVCH16374A is particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers. It can be used as two 8-bit flip-flops or one 16-bit flip-flop. On the positive transition of the clock (CLK) input, the Q outputs of the flip-flop take on the logic levels set up at the data (D) inputs.

DGG OR DL PACKAGE (TOP VIEW)



A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines without interface or pullup components.

OE does not affect internal operations of the flip-flop. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.



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description (continued)

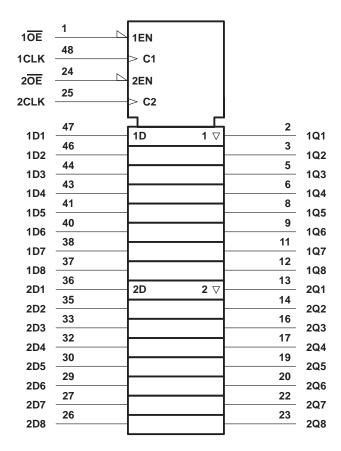
Active bus-hold circuitry is provided to hold unused or floating data inputs at a valid logic level.

The SN74LVCH16374A is characterized for operation from -40°C to 85°C.

FUNCTION TABLE (each flip-flop)

	•		
	INPUTS	OUTPUT	
OE	CLK	D	Q
L	↑	Н	Н
L	\uparrow	L	L
L	H or L	Χ	Q ₀
Н	X	Χ	Z

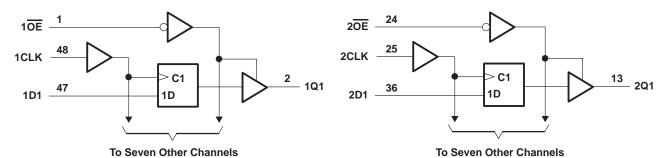
logic symbol†



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.



logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}	–0.5 V to 6.5 V
Input voltage range, V _I (see Note 1)	
Voltage range applied to any output in the high-impedance or power-off state, VO	
(see Note 1)	–0.5 V to 6.5 V
Voltage range applied to any output in the high or low state, VO	
(see Notes 1 and 2)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)	–50 mA
Output clamp current, I _{OK} (V _O < 0)	–50 mA
Continuous output current, I _O	±50 mA
Continuous current through each V _{CC} or GND	±100 mA
Package thermal impedance, θ _{JA} (see Note 3): DGG package	89°C/W
DL package	94°C/W
Storage temperature range, T _{stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. The value of V_{CC} is provided in the recommended operating conditions table.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			MIN	MAX	UNIT			
V	Supply voltage	Operating	1.65	3.6	V			
Vcc	Supply voltage	Data retention only	1.5		V			
		V _{CC} = 1.65 V to 1.95 V	0.65 × V _{CC}					
V_{IH}	High-level input voltage	V _{CC} = 2.3 V to 2.7 V	1.7		V			
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2					
		V _{CC} = 1.65 V to 1.95 V		0.35 × V _{CC}				
V_{IL}	Low-level input voltage	V _{CC} = 2.3 V to 2.7 V		0.7	V			
		V _{CC} = 2.7 V to 3.6 V		0.8				
٧ı	Input voltage	•	0	5.5	V			
VO	Outros to calta a a	High or low state	0	Vcc	\/			
	Output voltage	3 state	0	5.5	V			
		V _{CC} = 1.65 V		-4	A			
1	High-level output current	V _{CC} = 2.3 V		-8				
ЮН		V _{CC} = 2.7 V		-12	mA			
		V _{CC} = 3 V		-24				
		V _{CC} = 1.65 V		4				
	Low-level output current	V _{CC} = 2.3 V		8				
IOL		V _{CC} = 2.7 V		12	mA			
		V _{CC} = 3 V		24				
Δt/Δν	Input transition rise or fall rate	0	10	ns/V				
T _A	Operating free-air temperature		-40	85	°C			

NOTE 4: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIO	NS	Vcc	MIN	TYPT MAX	UNIT
	I _{OH} = -100 μA		1.65 V to 3.6 V	V _{CC} -0.	2	
	$I_{OH} = -4 \text{ mA}$	1.65 V	1.2			
Va	$I_{OH} = -8 \text{ mA}$	2.3 V	1.7			
VOH	I _{OH} = -12 mA		2.7 V	2.2		v
	10H = -12 111A		3 V	2.4		
	I _{OH} = -24 mA		3 V	2.2		
	$I_{OL} = 100 \mu A$		1.65 V to 3.6 V		0.2	
	I _{OL} = 4 mA		1.65 V		0.45	
VOL	I _{OL} = 8 mA		2.3 V		0.7	V
	I _{OL} = 12 mA	2.7 V		0.4]	
	I _{OL} = 24 mA		3 V		0.55	
ΙΙ	V _I = 0 to 5.5 V		3.6 V		±5	μΑ
	V _I = 0.58 V	1.65 V	‡]	
	V _I = 1.07 V		‡		μΑ	
	V _I = 0.7 V	2.3 V	45			
I _I (hold)	V _I = 1.7 V	2.5 V	-45			
	V _I = 0.8 V	3 V	75			
	V _I = 2 V		-75			
	V _I = 0 to 3.6 V§		3.6 V		±500	
l _{off}	V_I or $V_O = 5.5 V$		0		±10	μΑ
loz	$V_0 = 0 \text{ to } 5.5 \text{ V}$		3.6 V		±10	μА
	V _I = V _{CC} or GND	1- 0	3.6 V		20	
lcc	$3.6 \text{ V} \le \text{V}_{\text{I}} \le 5.5 \text{ V}^{\P}$	IO = 0	3.6 V		20	μΑ
ΔICC	One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND		2.7 V to 3.6 V		500	μА
Ci	V _I = V _{CC} or GND		3.3 V		5	pF
Co	$V_O = V_{CC}$ or GND		3.3 V		6.5	pF

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

			V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT	
		MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
fclock	Clock frequency		‡		‡		150		150	MHz
t _W	Pulse duration, CLK high or low	‡		‡		3.3		3.3		ns
t _{su}	Setup time, data before CLK↑	‡		‡		1.9		1.9		ns
t _h	Hold time, data after CLK↑	‡		‡		1.1		1.1		ns

[‡] This information was not available at the time of publication.



[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$. ‡ This information was not available at the time of publication.

[§] This is the bus-hold maximum dynamic current required to switch the input from one state to another.

[¶] This applies in the disabled state only.

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switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V ± 0.15 V		V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(INFOT)	(001F01)	MIN	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
f _{max}			†		†		150		150		MHz
^t pd	CLK	Q	†	†	†	†		4.9	1.5	4.5	ns
t _{en}	ŌĒ	Q	†	†	†	†		5.3	1.5	4.6	ns
t _{dis}	ŌĒ	Q	†	†	†	†		6.1	1.5	5.5	ns
t _{sk(o)} ‡										1	ns

[†] This information was not available at the time of publication.

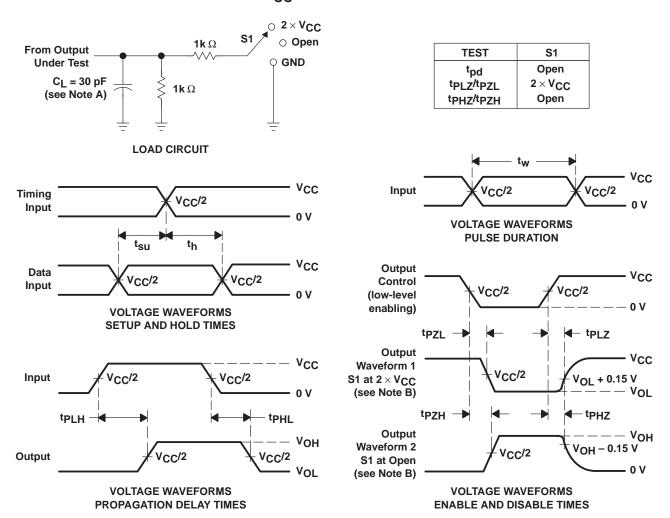
operating characteristics, T_A = 25°C

	PARAMETER	TEST CONDITIONS	V _{CC} = 1.8 V ± 0.15 V	V _{CC} = 2.5 V ± 0.2 V	V _{CC} = 3.3 V ± 0.3 V	UNIT		
			CONDITIONS	TYP	TYP	TYP		
Card	Power dissipation capacitance	Outputs enabled	f = 10 MHz	†	†	58	pF	
C _{pd}	per flip-flop	Outputs disabled	1 = 10 MH2	†	†	24		

[†] This information was not available at the time of publication.

[‡] Skew between any two outputs of the same package switching in the same direction

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 1.8 \text{ V} \pm 0.15 \text{ V}$



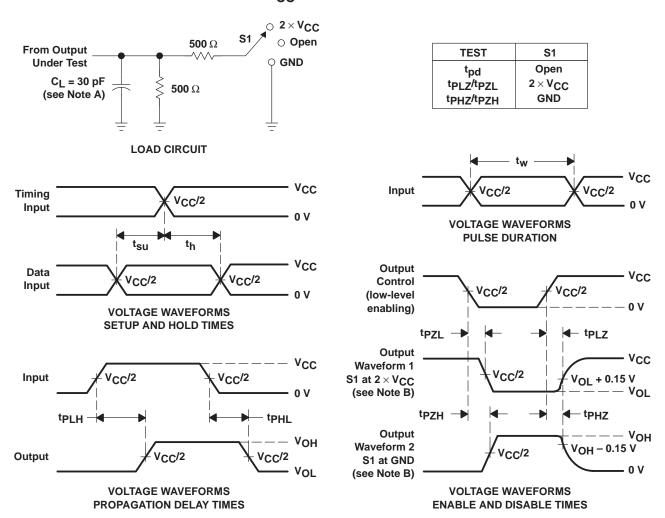
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_f \leq 2$ ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms

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PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 \text{ V} \pm 0.2 \text{ V}$



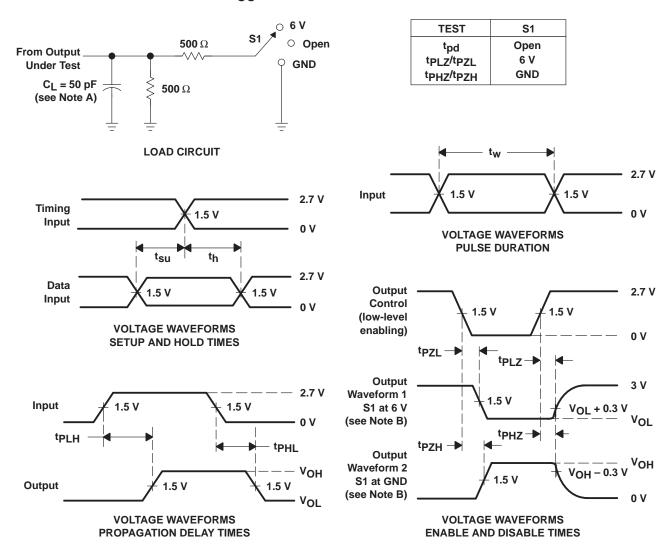
NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzl and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.7 \text{ V}$ AND 3.3 V \pm 0.3 V



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \,\Omega$, $t_f \leq 2.5 \,\text{ns}$, $t_f \leq 2.5 \,\text{ns}$.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLz and tpHz are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tpLH and tpHL are the same as tpd.

Figure 3. Load Circuit and Voltage Waveforms



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